Application/Control No. 10/031,399 Examiner Tianjie Chen Applicant(s)/Patent Under Reexamination SATOH, KATSUHISA Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
,	Α	US-6,345,030 B1	02-2002	Sakurai et al.	369/192
1	- В.	, US-6,414,929 B1	07-2002	Fujiwara, Tatsunori	369/77.1
	C	US-6,646,973 B2	11-2003	Kikuchi et al.	369/77.1
	D	US-5,986,981 A	11-1999	Takemasa et al.	369/30.9
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J,	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.